

REMARKS

Claims 1-30 are pending in this application. By this Amendment, new claims 29-30 are added.

In response to the restriction requirement within the Office Action dated April 19, applicants hereby elect Group I (claims 1-8 and 30), with traverse, for prosecution on the merits. Applicants also elect "embodiment 2: figures 4-5" as identified in the Office Action. At least claims 1-8 and 30 of the elected Group I read on Figures 4-5, although as explained below all claims 1-30 read on "embodiment 2: Figures 4-5." Applicants also expressly states that "embodiment 1" and "embodiment 2" are terminologies of the Office Action and not that of applicant.

It is respectfully submitted that all claims 1-30 should be examined in a single application. For example, each of independent claims 1, 9, 17 and 23 contains similar features that should all be examined concurrently. For example, independent claim 1 includes the claimed feature(s) that "the magnetic material including a structure to reduce Eddy currents flowing in the magnetic material." This exact same language is provided in independent claim 23. Thus both of independent claims 1 and 23 should be examined together to avoid repetitive examination of similar features.

Further, dependent claims 10 and 18 (depending from independent claims 9 and 17) also very similarly recite "one of the slots and the laminated structure reduces Eddy currents flowing in the magnetic material." These very similar features will be examined with independent claims 9 and 17 (i.e., Groups II and III). Thus, both independent claims 9 and 17 should be examined with independent claim 1 to avoid repetitive examination of similar features.

Additionally, dependent claim 30 (depending from independent claim 1) recites the plurality of metal lines and the magnetic material are provided on a die. Dependent claim 29 (depending from independent claim 23) also relates to features on a die. The Office Action indicates that claims 9-16 (Group II) are directed to a chip. However, features of “a chip” or “a die” are being examined in other groups of claims. If dependent claim features of an elected group are being examined, and that claimed feature is the basis for the formation of another group of claims, then all those claims should be examined together. That is, dependent claims 29-30 (of Groups I and IV) and independent claim 17 (of Group III) both specifically relate to a chip or die. Thus, Group II should clearly be examined with Group I (along with Groups III and IV) to avoid repetitive examination.

Even further, it is respectfully submitted that the above discussed features relating to “a structure to reduce Eddy currents flowing in the magnetic material” are shown in the “embodiment 2: Figures 4-5.” The examination of all claims 1-30 should occur within one application in view of the similar subject matter of the different groups of claims and the discussion regarding Figures 4-5, which relates to each of the claims. The Examiner’s attention is directed to the discussion of Figures 4-5 on page 7, line 12-page 10, line 6 of the present specification. Clearly this section of the specification is relevant to each of the identified groups of claims (i.e., all Groups I-IV). Therefore all the claims 1-30 should be examined together to avoid unnecessary prosecution (for both the Patent Office and applicants).

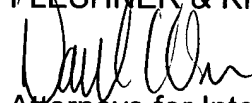
It is respectfully submitted that the subject matter of each of Groups I-IV is sufficiently related that a thorough search for the subject matter of each of the Groups would encompass a search for the subject matter of the remaining designated inventions.

Thus, it is respectfully submitted that the search and examination of the entire application could be made without serious burden. See MPEP §803 in which it states that "if the search and examination of an entire application can be made without serious burden, the Examiner must examine it on the merits, even though it includes claims to distinct or independent inventions" (emphasis added). It is respectfully submitted that this policy should apply in the present application in order to avoid unnecessary delay and expense to applicants and duplicative examination by the U.S. Patent and Trademark Office.

If the Examiner believes that any additional changes would place the application in better condition for allowance, the Examiner is invited to contact the undersigned attorney, **David C. Oren**, at the telephone number listed below.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 16-0607 and please credit any excess fees to such deposit account.

Respectfully submitted,
FLESHNER & KIM, LLP



Attorneys for Intel Corporation
Mark L. Fleshner
Registration No. 34,596
David C. Oren
Registration No. 38,694

P.O. Box 221200
Chantilly, Virginia 20153-1200
(703) 766-3701 DCO/kah
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